

February 2006

FDS8984

N-Channel PowerTrench® MOSFET

30V, 7A, 23m Ω

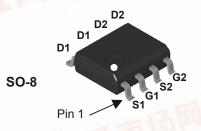
General Description

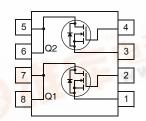
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(ON)}$ and fast switching speed.

Features

- Max $r_{DS(on)} = 23m\Omega$, $V_{GS} = 10V$, $I_D = 7A$
- Max $r_{DS(on)} = 30m\Omega$, $V_{GS} = 4.5V$, $I_D = 6A$
- Low gate charge
- 100% R_G tested
- RoHS Compliant







MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		30	V
V _{GS}	Gate to Source Voltage		±20	V
_	Drain Current Continuous	(Note 1a)	7	Α
ID	Pulsed		30	A
E _{AS}	Single Pulse Avalache Energy	(Note 2)	32	mJ
D	Power Dissipation for Single Operation		1.6	W
P_D	Derate above 25°C		13	mW/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8984	FDS8984	SO-8	330mm	12mm	2500 units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu A$, referenced to $25^{\circ}C$		23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V$ $V_{GS} = 0V$ $T_{J} = 125^{\circ}C$			1 250	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

On Characteristics (Note 3)

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2	1.7	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25°C		- 4.3		mV/°C
		$V_{GS} = 10V, I_{D} = 7A$		19	23	
rna	Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 6A$		24	30	mΩ
r _{DS(on)}	Brain to Source Off Hesistance	$V_{GS} = 10V, I_D = 7A,$ $T_J = 125^{\circ}C$		26	32	11152

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 0V	475	635	pF
Coss	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1.0MHz	100	135	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.00112	65	100	pF
R_{G}	Gate Resistance	f = 1MHz	0.9	1.6	Ω

Switching Characteristics (Note 3)

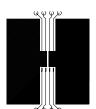
t _{d(on)}	Turn-On Delay Time		5	10	ns
t _r	Rise Time	V _{DD} = 15V, I _D = 7A	9	18	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V$, $R_{GS} = 33\Omega$	42	68	ns
t _f	Fall Time		21	34	ns
Qg	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 10V,$ $I_{D} = 7A$	9.2	13	nC
Q_g	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 5V,$	5.0	7	nC
Q _{gs}	Gate to Source Gate Charge	I _D = 7A	1.5		nC
Q _{gd}	Gate to Drain "Miller" Charge		2.0		nC

Drain-Source Diode Characteristics

V Course to Drain Diade Veltage	I _{SD} = 7A	0.9	1.25	V	
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 2.1A	0.8	1.0	V
t _{rr}	Diode Reverse Recovery Time	I _F = 7A, di/dt = 100A/μs		33	ns
Q _{rr}	Diode Reverse Recovery Charge			20	nC

Notes:

^{1:} R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 78°C/W when mounted on a 0.5in² pad of 2 oz copper



οφφω b) 125°C/W when mounted on a 0.02 in² pad of oz copper



c) 135°C/W when mounted on a minimun pad



Scale 1: 1 on letter size paper

- 2: Starting $T_J=25^{\circ}C$, L = 1mH, I $_{AS}$ = 8A, V $_{DD}$ = 27V, V $_{GS}$ = 10V. 3: Pulse Test:Pulse Width <300 μ S, Duty Cycle <2%.



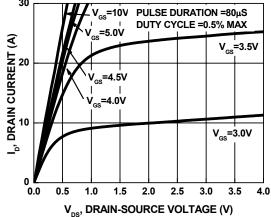


Figure 1. On Region Characteristics

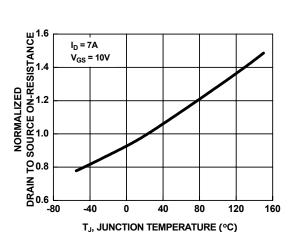
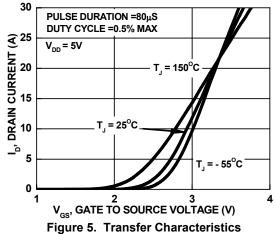


Figure 3. On Resistance vs Temperature



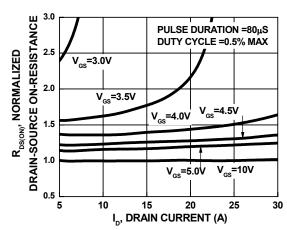


Figure 2. On-Resistance vs Drain Current and **Gate Voltage**

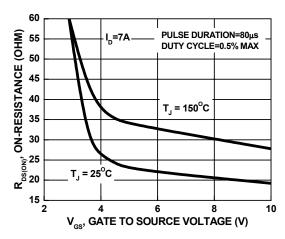


Figure 4. On-Resistance vs Gate to Source Votlage

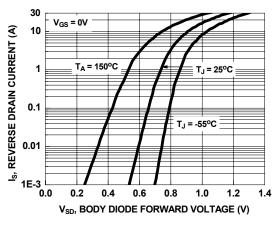


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



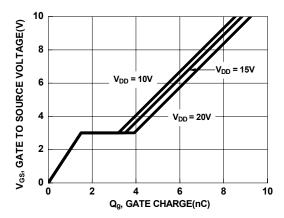


Figure 7. Gate Charge Characteristics

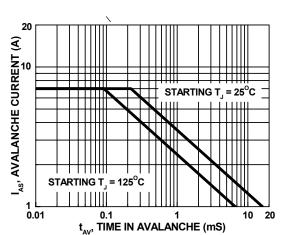


Figure 9. Unclamped Inductive Switching Capability

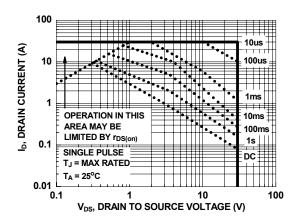


Figure 11. Forward Bias Safe Operating Area

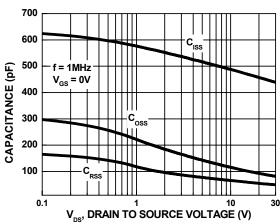


Figure 8. Capacitance vs Drain to Source Voltage

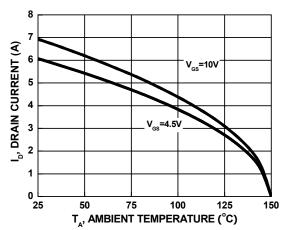


Figure 10. Maximum Continuous Drain Current vs
Ambient Temperature

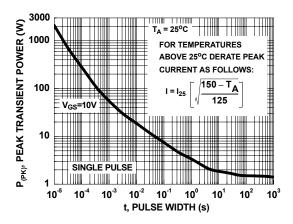


Figure 12. Single Pulse Maximum Power Dissipation

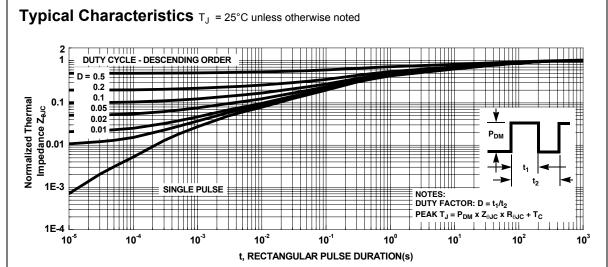


Figure 13. Transient Thermal Response Curve

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